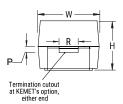


## T493D107K010BC6110

T493 HRA, Tantalum, MnO2 Tantalum, HRA, 100 uF, 10%, 10 VDC, SMD, MnO2, Molded, High Reliability, B (0.1%/1000 Hrs), 700 mOhms, 7343, 3.1 mm, 1.3 mm

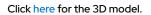
CATHODE (-) END VIEW



ANODE (+) END VIEW

BOTTOM VIEW

SIDE VIEW



General Information	
Series	T493 HRA
Dielectric	MnO2 Tantalum
Style	SMD Chip
Description	SMD, MnO2, Molded, High Reliability
Features	High Reliability
RoHS	No
Prop 65	WARNING: Cancer and reproductive harm - https://www.p65warnings.ca.gov /
SCIP Number	652b281f-d242-4453-bc44-06 55d646cec3
Termination	Hot Solder Dipped
AEC-Q200	No
Typical Component Weight	412.33 mg
Notes	P and R dimensions represents the minimum solderable area of the termination surface entirely below cutout (if one is present).

Dimensions	
L	7.3mm +/-0.3mm
W	4.3mm +/-0.3mm
н	2.8mm +/-0.3mm
т	0.13mm REF
S	1.3mm +/-0.3mm
F	2.4mm +/-0.1mm
A	3.8mm MIN
В	0.5mm +/-0.15mm
E	3.5mm REF
G	3.5mm REF
Р	0.5mm MIN
R	1mm REF
Х	0.1mm +/-0.1mm REF

Specifications	
Capacitance	100 uF
Tolerance	10%
Voltage DC	10 VDC (85C), 6.7 VDC (125C)
Temperature Range	-55/+125°C
Rated Temperature	85°C
Dissipation Factor	8% 120Hz 25C
Failure Rate	B (0.1%/1000 Hrs)
ESR	0.7 Ohms (100kHz 25C)
Ripple Current	463 mA (rms, 100kHz 25C)
Leakage Current	10 uA (5min 25°C)
Testing and Reliability	Standard Testing Only

## Packaging SpecificationsPackagingT&R, 178mmPackaging Quantity500

Statements of suitability for certain applications are based on our knowledge of typical operating conditions for such applications, but are not intended to constitute - and we specifically disclaim - any warranty concerning suitability for a specific customer application or use. This Information is intended for use only by customers who have the requisite experience and capability to determine the correct products for their application. Any technical advice inferred from this Information or otherwise provided by us with reference to the use of our products is given gratis, and we assume no obligation or liability for the advice given or results obtained.